

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

Product Summary



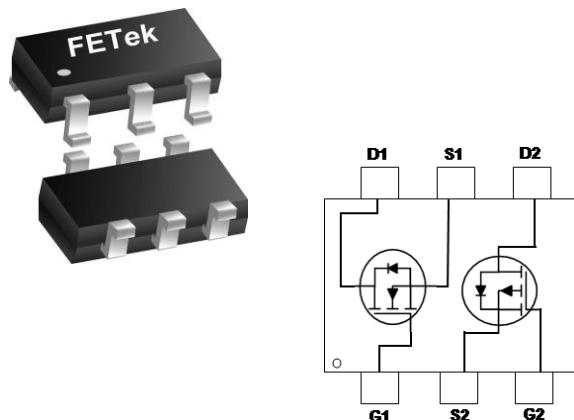
BVDSS	RDS(ON)	ID
30V	60mΩ	3.8A
-30V	115 mΩ	-2.3A

Description

The FKQ3909 is the high performance complementary N-ch and P-ch MOSFETs with high cell density, which provides excellent RDS(ON) and efficiency for most of the small power switching and load switch applications.

The FKQ3909 meet the RoHS and Green Product requirement with full function reliability approved.

TSOP6 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-Channel	P-Channel	
V _{DS}	Drain-Source Voltage	30	30	V
V _{GS}	Gate-Source Voltage	±12	±12	V
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 4.5V ¹	3.8	-2.3	A
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 4.5V ¹	3	-1.8	A
I _{DM}	Pulsed Drain Current ²	16	-15	A
P _D @T _C =25°C	Total Power Dissipation ³	1.1	1.1	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-ambient ¹	---	110	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	---	70	°C/W



FETek Technology Corp.

FKQ3909

N-Ch and P-Ch 30V Fast Switching MOSFETs

N-Channel Electrical Characteristics ($T_J=25^\circ C$, unless otherwise noted)

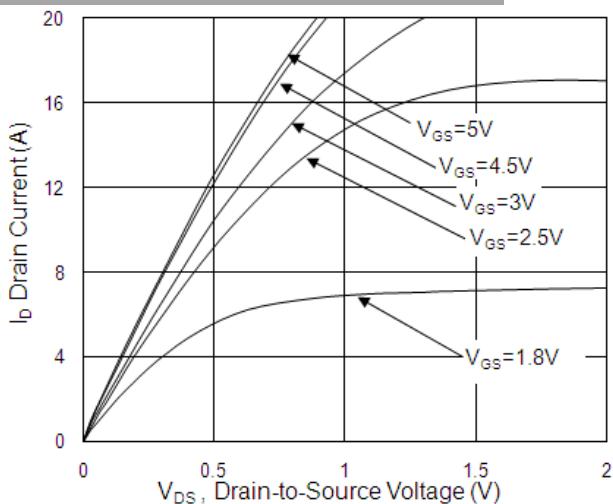
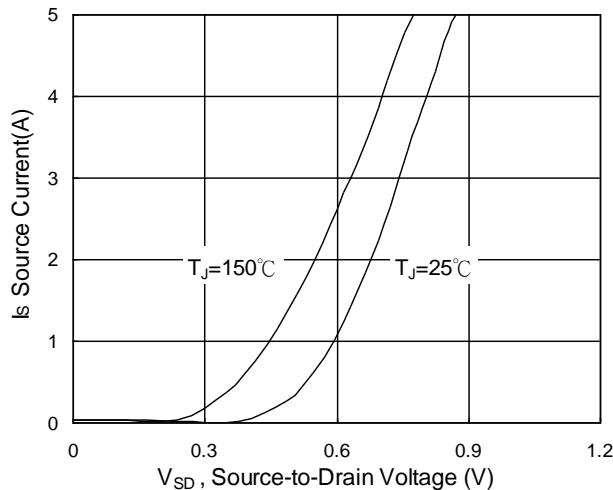
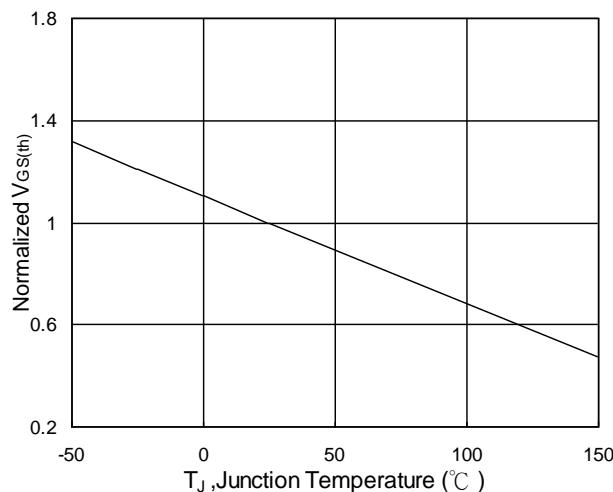
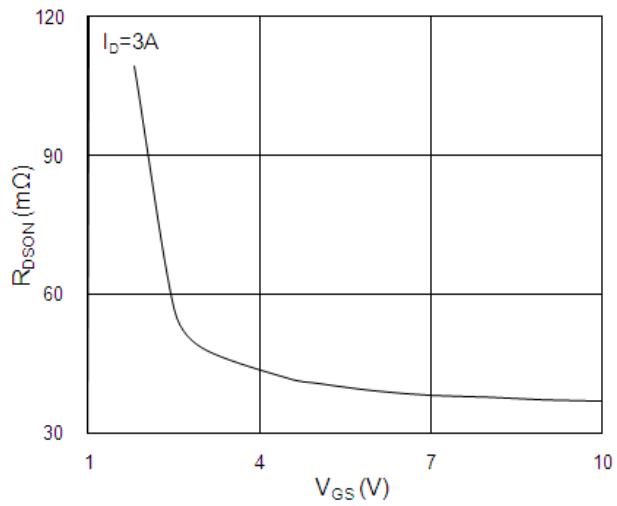
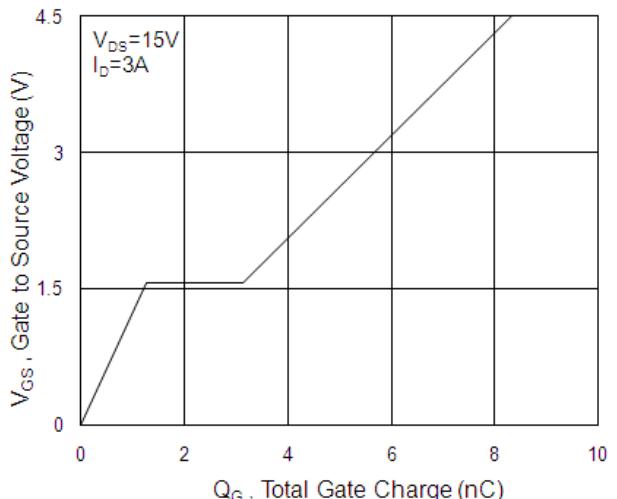
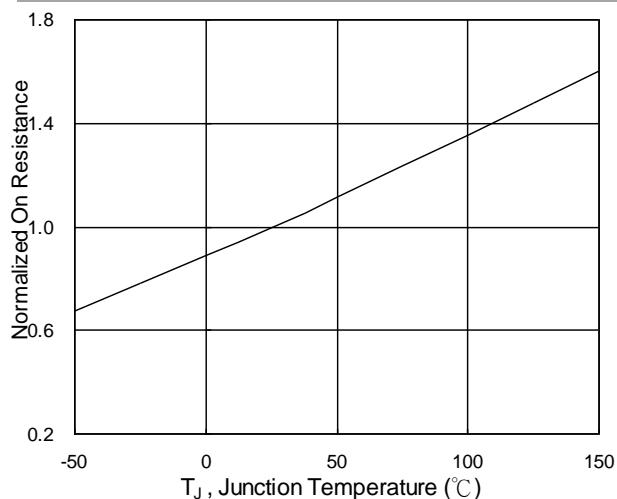
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30	---	---	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance ²	$V_{GS}=10V, I_D=3.4A$	---	52	60	$m\Omega$
		$V_{GS}=4.5V, I_D=3A$	---	57	65	
		$V_{GS}=2.5V, I_D=2A$	---	70	85	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	0.4	---	1.2	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=24V, V_{GS}=0V, T_J=25^\circ C$	---	---	1	μA
		$V_{DS}=24V, V_{GS}=0V, T_J=55^\circ C$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=5V, I_D=3.4A$	---	6	---	S
Q_g	Total Gate Charge (4.5V)	$V_{DS}=15V, V_{GS}=4.5V, I_D=3A$	---	8.4	---	nC
Q_{gs}	Gate-Source Charge		---	1.6	---	
Q_{gd}	Gate-Drain Charge		---	1.8	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=10V, V_{GS}=4.5V, R_G=3.3\Omega$	---	3.2	---	ns
T_r	Rise Time		---	41.8	---	
$T_{d(off)}$	Turn-Off Delay Time		---	21.2	---	
T_f	Fall Time		---	6.4	---	
C_{iss}	Input Capacitance	$V_{DS}=15V, V_{GS}=0V, f=1MHz$	---	662	---	pF
C_{oss}	Output Capacitance		---	52	---	
C_{rss}	Reverse Transfer Capacitance		---	45	---	

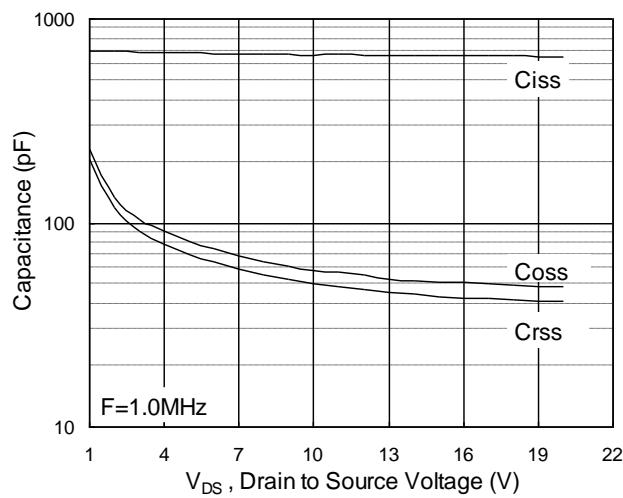
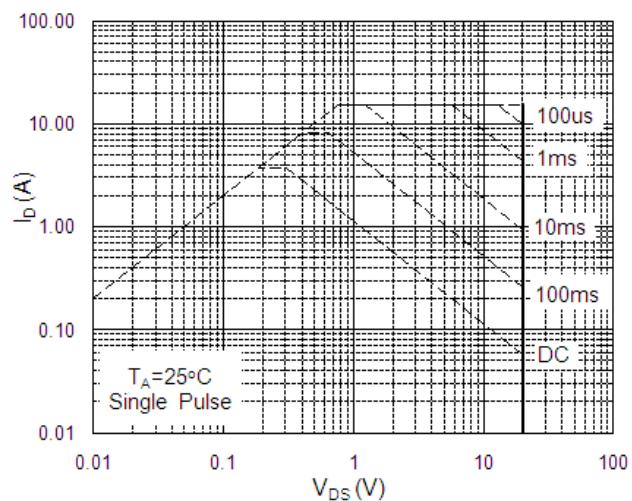
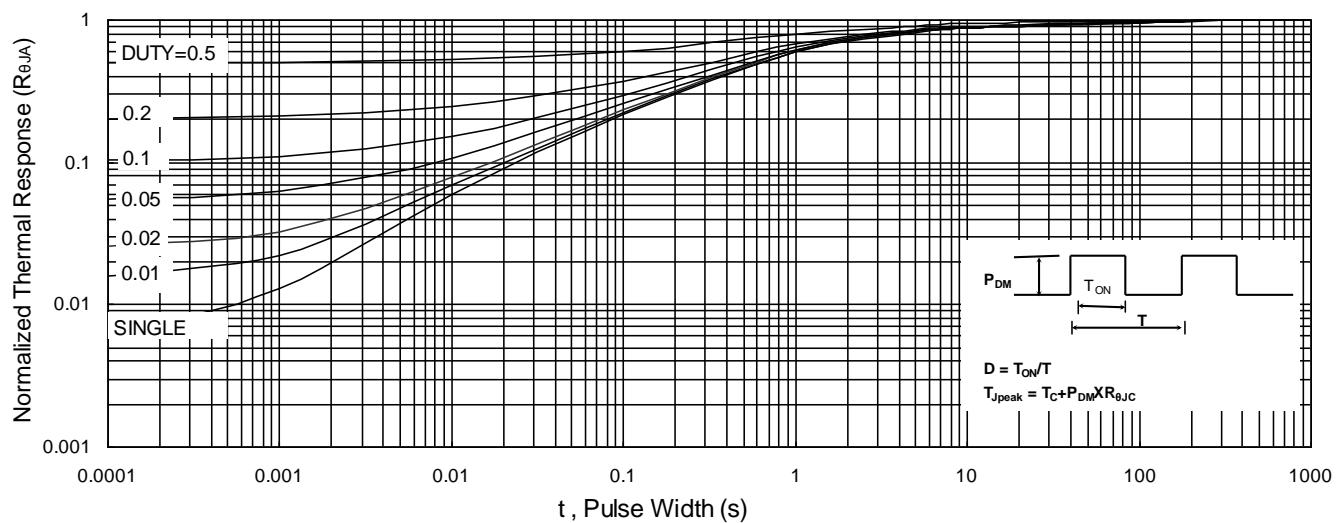
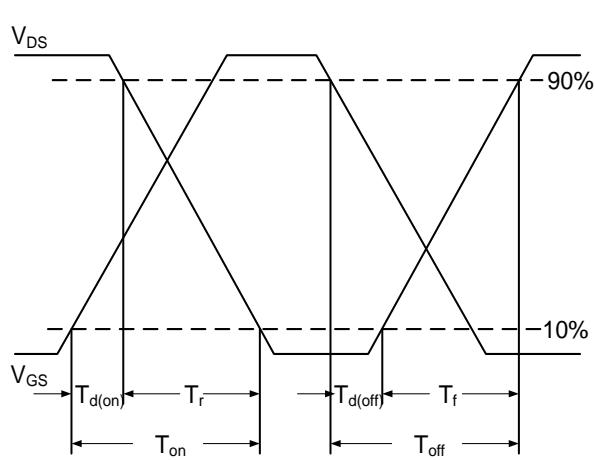
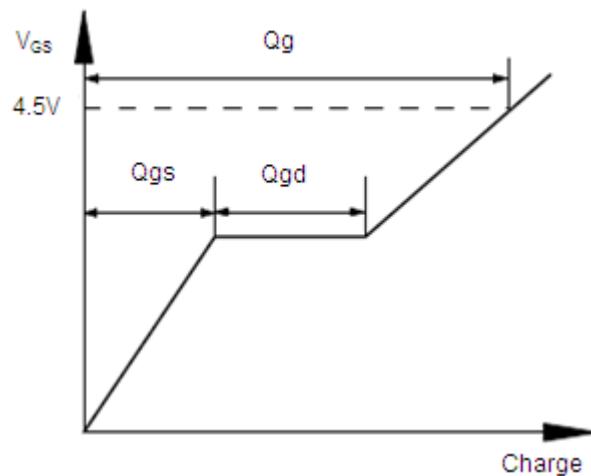
Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,4}	$V_G=V_D=0V$, Force Current	---	---	3.8	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0V, I_s=1A, T_J=25^\circ C$	---	---	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3.The power dissipation is limited by $150^\circ C$ junction temperature
- 4.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

N-Channel Typical Characteristics

Fig.1 Typical Output Characteristics

Fig.3 Forward Characteristics of Reverse

Fig.5 Normalized $V_{GS(th)}$ vs. T_J

Fig.2 On-Resistance vs. Gate-Source

Fig.4 Gate-Charge Characteristics

Fig.6 Normalized $R_{DS(on)}$ vs. T_J

N-Ch and P-Ch 30V Fast Switching MOSFETs

Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance

Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform



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N-Ch and P-Ch 30V Fast Switching MOSFETs

P-Channel Electrical Characteristics ($T_J=25^\circ C$, unless otherwise noted)

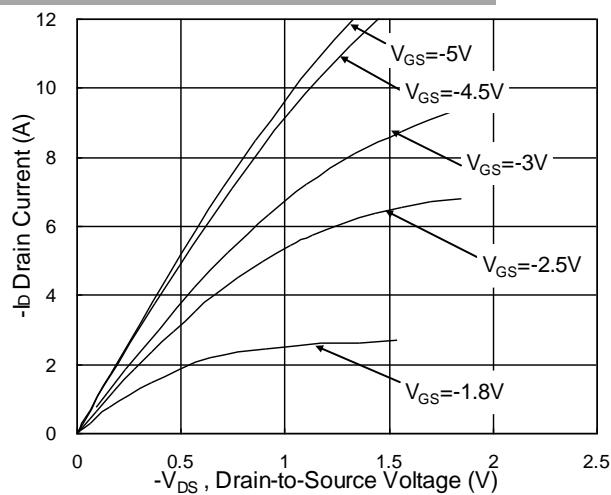
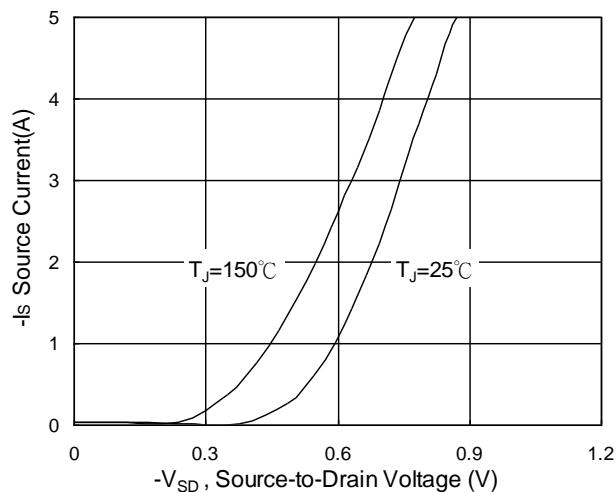
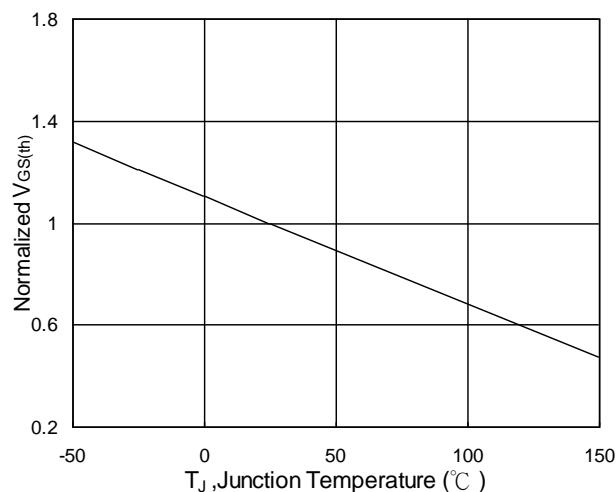
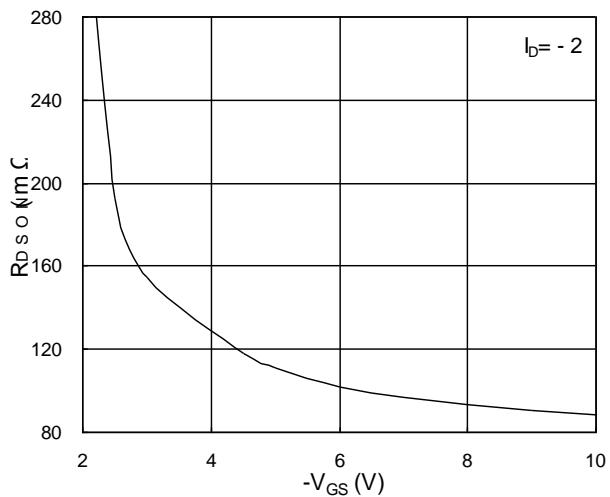
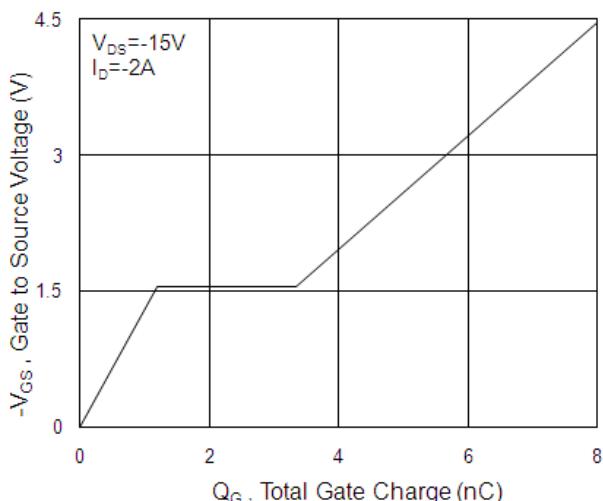
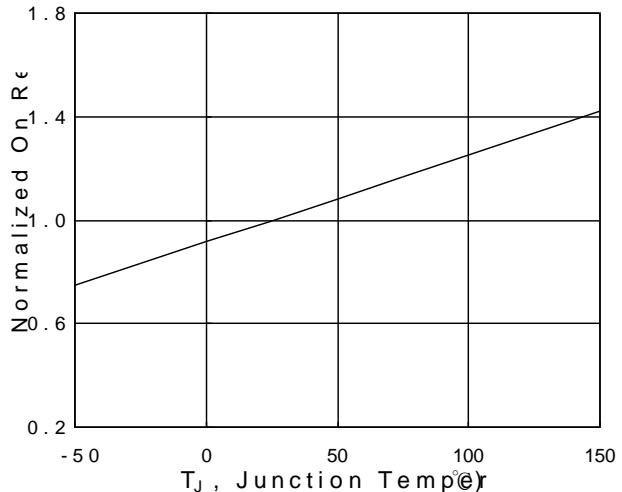
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$R_{DS(ON)}$	Static Drain-Source On-Resistance ²	$V_{GS}=-10V, I_D=-2.3A$	---	85	115	$m\Omega$
		$V_{GS}=-4.5V, I_D=-2A$	---	105	145	
		$V_{GS}=-2.5V, I_D=-1A$	---	145	200	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-0.4	---	-1.2	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=-24V, V_{GS}=0V, T_J=25^\circ C$	---	---	1	μA
		$V_{DS}=-24V, V_{GS}=0V, T_J=55^\circ C$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=-5V, I_D=-2.3A$	---	5.3	---	S
Q_g	Total Gate Charge (-4.5V)	$V_{DS}=-15V, V_{GS}=-4.5V, I_D=-2A$	---	8.1	---	nC
Q_{gs}	Gate-Source Charge		---	1.2	---	
Q_{gd}	Gate-Drain Charge		---	2.1	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=-10V, V_{GS}=-4.5V, R_G=3.3\Omega$	---	4	---	ns
T_r	Rise Time		---	33.2	---	
$T_{d(off)}$	Turn-Off Delay Time		---	26	---	
T_f	Fall Time		---	11.6	---	
C_{iss}	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1MHz$	---	710	---	pF
C_{oss}	Output Capacitance		---	79	---	
C_{rss}	Reverse Transfer Capacitance		---	57	---	

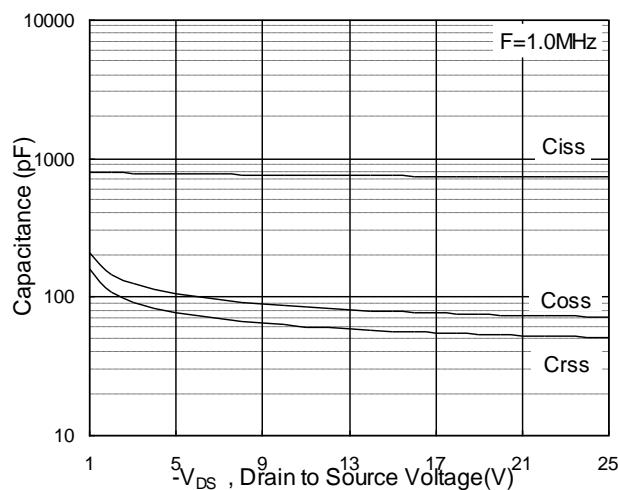
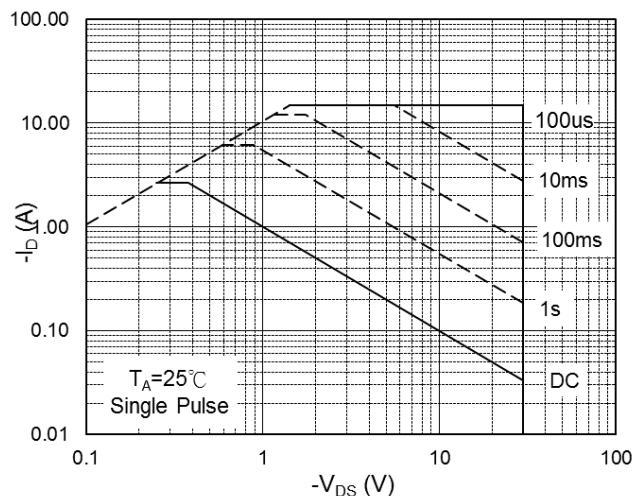
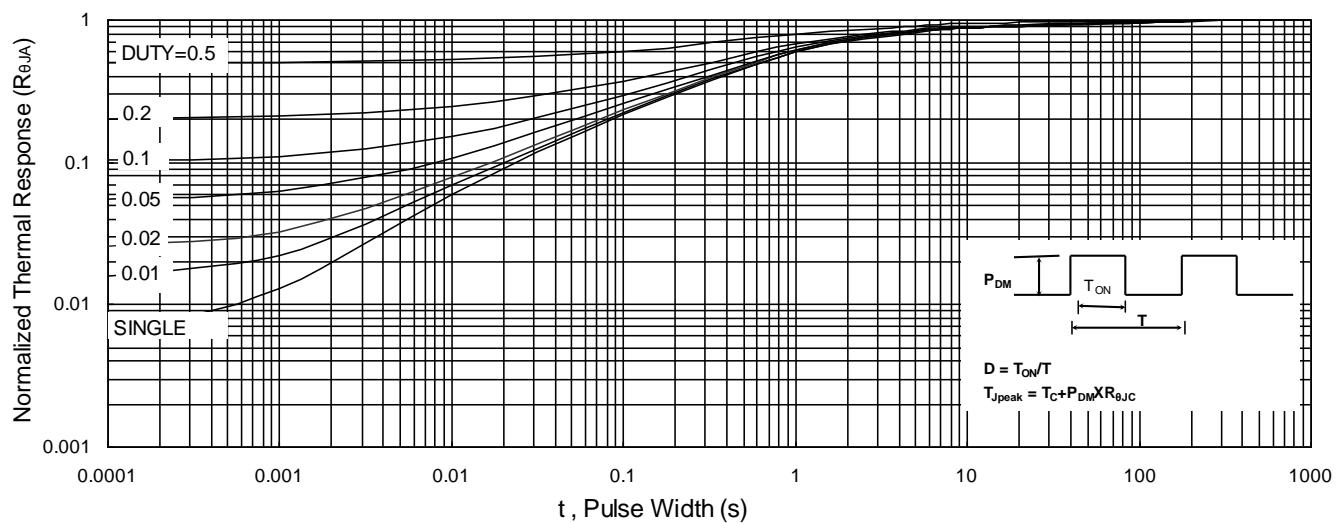
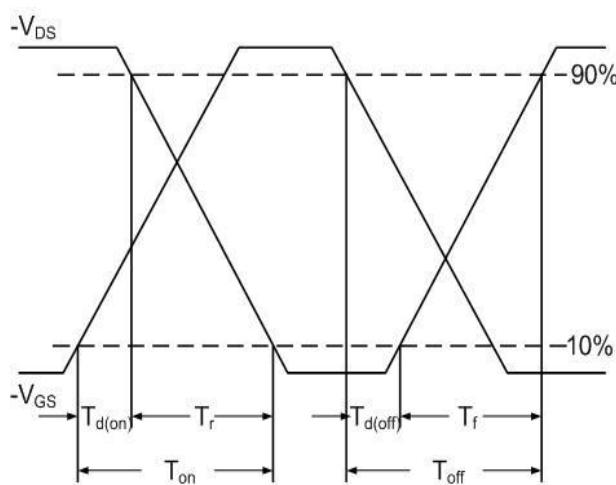
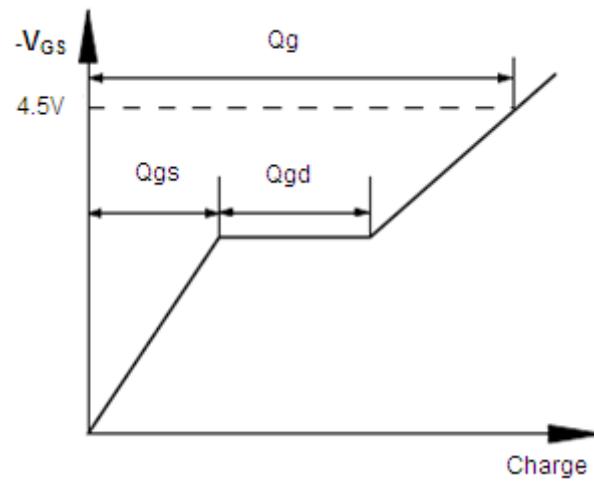
Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,4}	$V_G=V_D=0V$, Force Current	---	---	-2.3	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0V, I_s=-1A, T_J=25^\circ C$	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
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